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(54) **Beam deflecting method, beam deflector, ion implantation method, and ion implantation system**

(57) The present invention provides for a beam deflecting method, beam deflector, ion implantation method, and ion implantation system in which a beam deflector for scanning performs deflection of a charged particle beam having a regular trajectory in a vacuum space to thereby periodically change the trajectory of the charged particle beam. The beam deflector comprises a pair of deflection electrodes disposed so as to confront each inner electrode surface having a symmetrical concave extending in a direction of a beam trajectory.

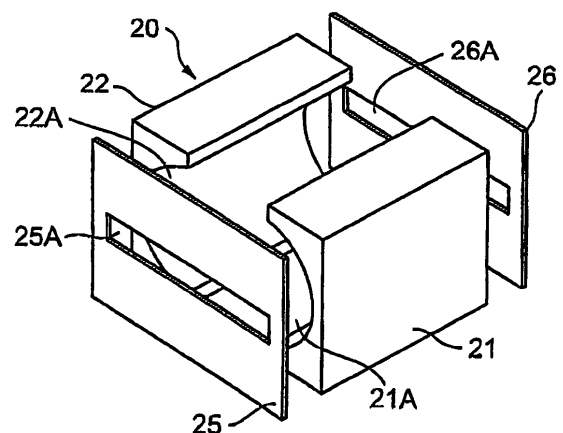


FIG. 2



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Application Number
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**ANNEX TO THE EUROPEAN SEARCH REPORT
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